

## **Boosting the activity of UiO-66(Zr) by defect engineering: efficient aldol condensation of furfural and MIBK for the production of bio jet-fuel precursors**

María Sanz<sup>a</sup>, Pedro Leo<sup>a</sup>, Carlos Palomino<sup>b</sup>, Marta Paniagua<sup>a</sup>, Gabriel Morales<sup>a,c</sup>, Juan A. Melero<sup>a,c,\*</sup>

<sup>a</sup> Chemical and Environmental Engineering Group. ESCET, Universidad Rey Juan Carlos. c/Tulipán s/n 28933 Móstoles, Spain.

<sup>b</sup> Department of Chemistry, University of the Balearic Islands, Cra. de Valldemossa, 07122, Spain.

<sup>c</sup> Instituto de Investigación de Tecnologías para la Sostenibilidad. ESCET, Universidad Rey Juan Carlos. c/Tulipán s/n 28933 Móstoles, Spain.

**Green Chemistry**

### **Electronic Supplementary Information**

\* Corresponding author:

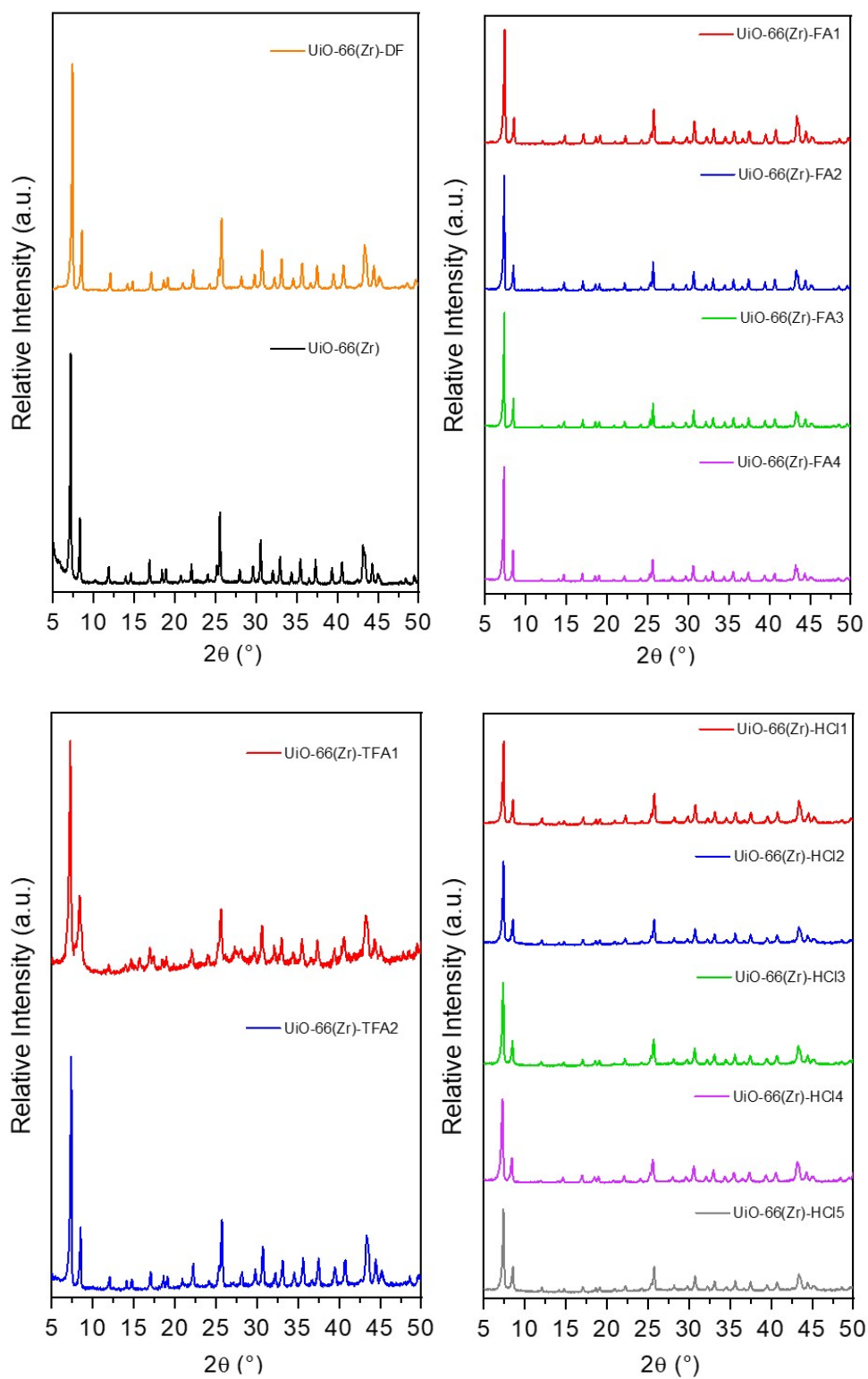
E-mail: [juan.melero@urjc.es](mailto:juan.melero@urjc.es)

Phone-number: +34-91 665 50 83

**Table ESI-1** Composition in the synthesis media for UiO-66(Zr) materials.

Sample Name	ZrCl <sub>4</sub> (mmol)	MOD (ml)	DMF (ml)	BDC (mmol)	C <sub>MOD</sub> (mol/L)	MOD/DMF (mol)	MOD/BDC (mol)
UiO-66(Zr)-DF	16.2	-	100	32.4	-	-	-
UiO-66(Zr)	6	-	100	6	-	-	-
Modulator: Formic Acid (pKa = 3.77)							
UiO-66(Zr)-FA1	6	2	98	6	0.51	0.04	8.45
UiO-66(Zr)-FA2	6	8	92	6	2.04	0.17	33.82
UiO-66(Zr)-FA3	6	16	84	6	4.07	0.38	67.63
UiO-66(Zr)-FA4	6	20	80	6	5.09	0.49	84.54
Modulator: Trifluoroacetic acid (pKa = 0.23)							
UiO-66(Zr)-TFA1	6	2	98	6	0.26	0.02	4.30
UiO-66(Zr)-TFA2	6	8	92	6	1.03	0.09	17.19
Modulator: Hydrochloric acid (pKa = -6.3)							
UiO-66(Zr)-HCl1	6	2	98	6	0.24	0.02	4.05
UiO-66(Zr)-HCl2	6	8	92	6	0.97	0.08	16.19
UiO-66(Zr)-HCl3	6	16	84	6	1.95	0.18	32.37
UiO-66(Zr)-HCl4	6	20	80	6	2.44	0.24	40.46
UiO-66(Zr)-HCl5	6	24	76	6	2.92	0.30	48.56

MOD = modulator; DMF = N,N'-dimethyl formamide; BDC = benzene-1,4-dicarboxilate.

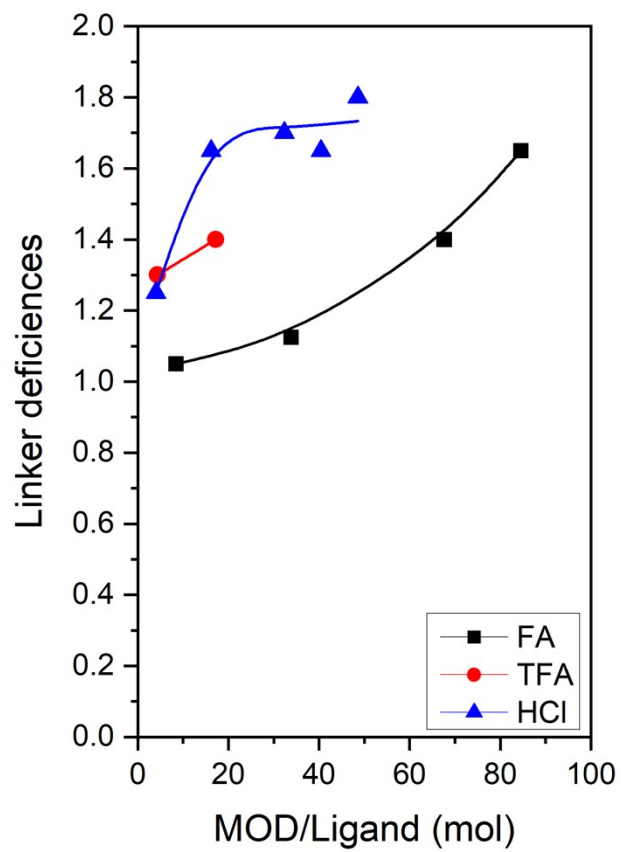


**Fig. ESI-1** Powder X-ray diffraction patterns of UiO-66(Zr)-DF, UiO-66(Zr) parent and modulated UiO-66(Zr) series of materials.

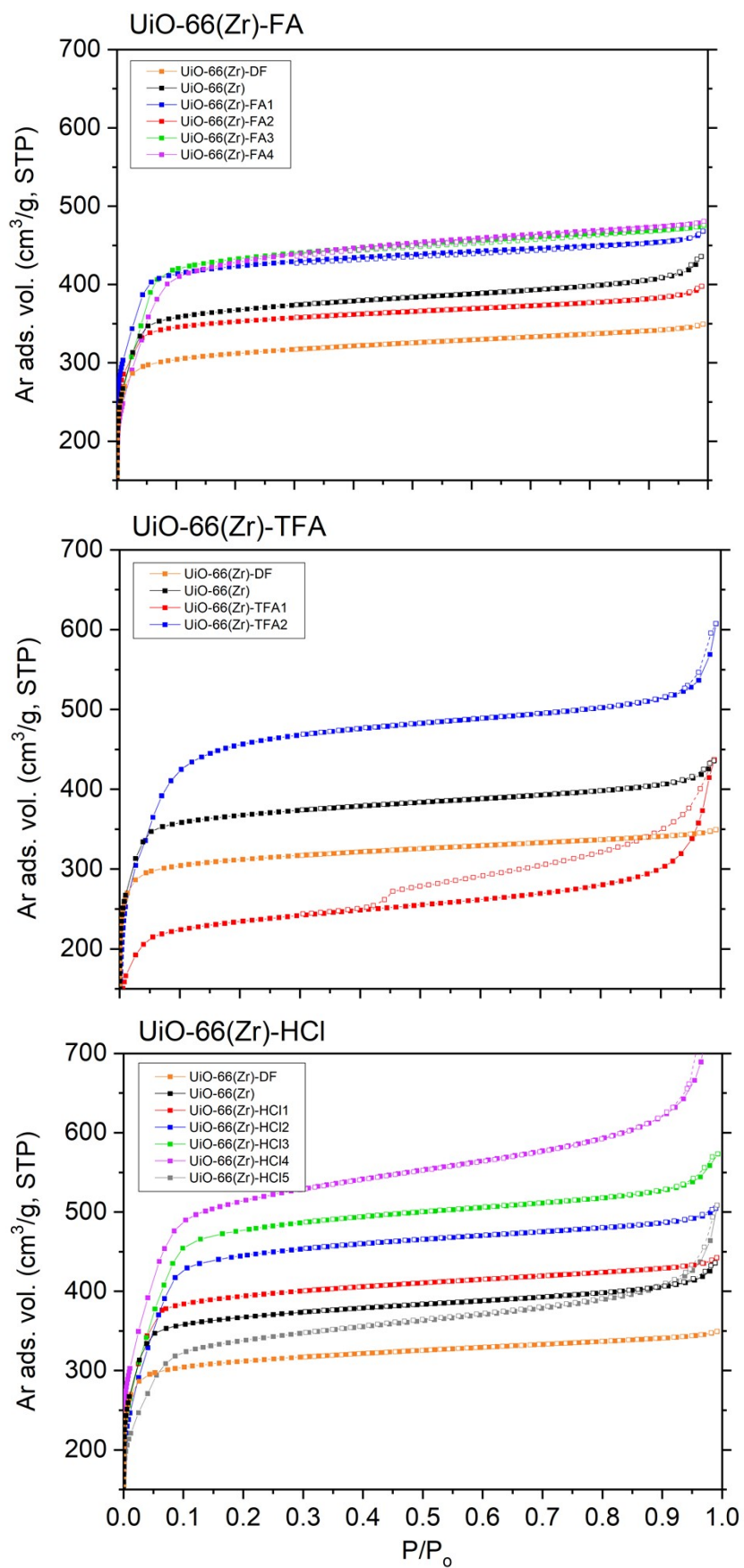
**Table ESI-2** Quantification of linker deficiencies in defective UiO-66 samples.

Sample	T <sub>plat</sub> (°C) <sup>a</sup>	W <sub>Exp-Plat</sub> (%) <sup>b</sup>	NL <sub>Exp</sub> <sup>c</sup>	x <sup>d</sup>	Composition at W <sub>Exp.Platt</sub> <sup>e</sup>
UiO-66(Zr)-DF	370	220	6.00	0.00	Zr <sub>6</sub> O <sub>6</sub> (BCD) <sub>6</sub>
UiO-66(Zr)	370	204	5.20	0.80	Zr <sub>6</sub> O <sub>6.8</sub> (BCD) <sub>5.2</sub>
UiO-66(Zr)-FA1	370	199	4.95	1.05	Zr <sub>6</sub> O <sub>7.05</sub> (BCD) <sub>4.95</sub>
UiO-66(Zr)-FA2	370	197	4.88	1.13	Zr <sub>6</sub> O <sub>7.13</sub> (BCD) <sub>4.87</sub>
UiO-66(Zr)-FA3	370	192	4.60	1.40	Zr <sub>6</sub> O <sub>7.4</sub> (BCD) <sub>4.6</sub>
UiO-66(Zr)-FA4	370	187	4.35	1.65	Zr <sub>6</sub> O <sub>7.65</sub> (BCD) <sub>4.35</sub>
UiO-66(Zr)-TFA1	390	194	4.70	1.30	Zr <sub>6</sub> O <sub>7.3</sub> (BCD) <sub>4.7</sub>
UiO-66(Zr)-TFA2	390	192	4.60	1.40	Zr <sub>6</sub> O <sub>7.4</sub> (BCD) <sub>4.6</sub>
UiO-66(Zr)-HCl1	370	195	4.75	1.25	Zr <sub>6</sub> O <sub>7.25</sub> (BCD) <sub>4.75</sub>
UiO-66(Zr)-HCl2	370	187	4.35	1.65	Zr <sub>6</sub> O <sub>7.65</sub> (BCD) <sub>4.35</sub>
UiO-66(Zr)-HCl3	370	186	4.30	1.70	Zr <sub>6</sub> O <sub>7.7</sub> (BCD) <sub>4.3</sub>
UiO-66(Zr)-HCl4	370	187	4.35	1.65	Zr <sub>6</sub> O <sub>7.65</sub> (BCD) <sub>4.35</sub>
UiO-66(Zr)-HCl5	370	184	4.20	1.80	Zr <sub>6</sub> O <sub>7.8</sub> (BCD) <sub>4.2</sub>

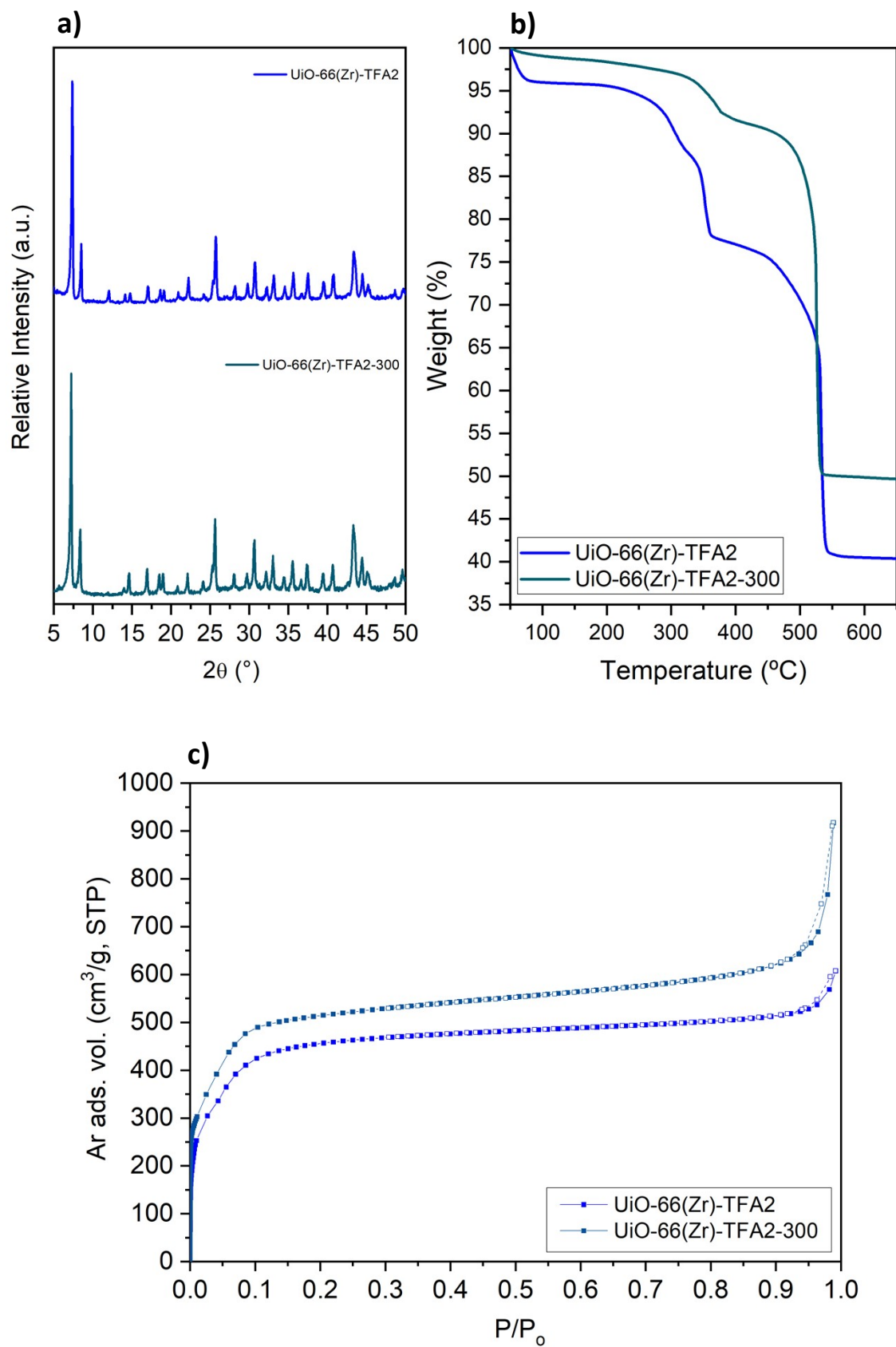
<sup>a</sup> Temperature of the plateau; <sup>b</sup> Experimental weight of the plateau; <sup>c</sup> Number of linkers per defective Zr<sub>6</sub> formula unit calculated as (W<sub>Exp-Plat</sub> - W<sub>End</sub>)/Wt.PL<sub>Theo</sub> being Wt.PL<sub>Theo</sub>=20 % when the end weight of the TGA run is normalized to 100 % (W<sub>End</sub> = 100 %); <sup>d</sup> Number of linker deficiencies per Zr<sub>6</sub> formula unit calculated as 6 - NL<sub>Exp</sub>; <sup>e</sup> Composition of the material assuming the following formula Zr<sub>6</sub>O<sub>6+x</sub>(BDC)<sub>6-x</sub>



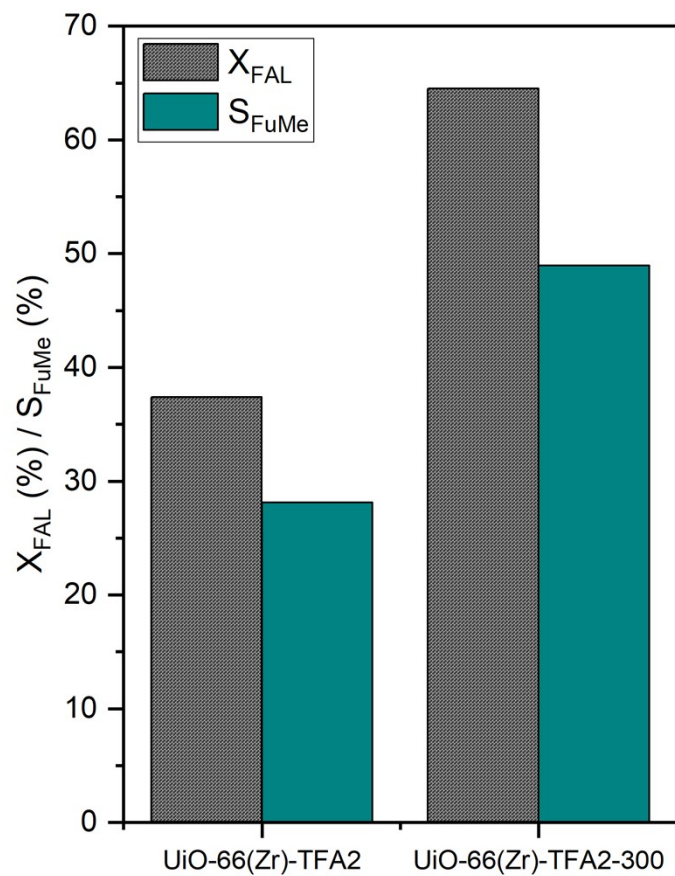
**Fig. ESI-2.** Linker deficiencies corresponding to modulated UiO-66(Zr) series of materials.



**Fig. ESI-3** Argon adsorption-desorption isotherms of UiO-66(Zr)-DF, UiO-66(Zr) parent and modulated UiO-66(Zr) series of materials.

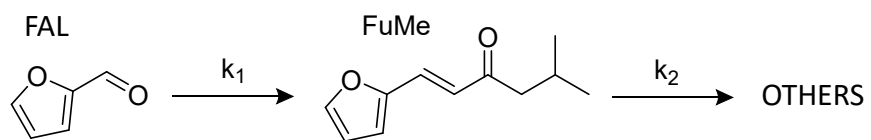


**Fig. ESI-4** a) Powder X-ray diffraction patterns; b) Thermogravimetry analysis, and c) Argon adsorption-desorption isotherms of UiO-66(Zr)-TFA2 and UiO-66(Zr)-TFA2-300.

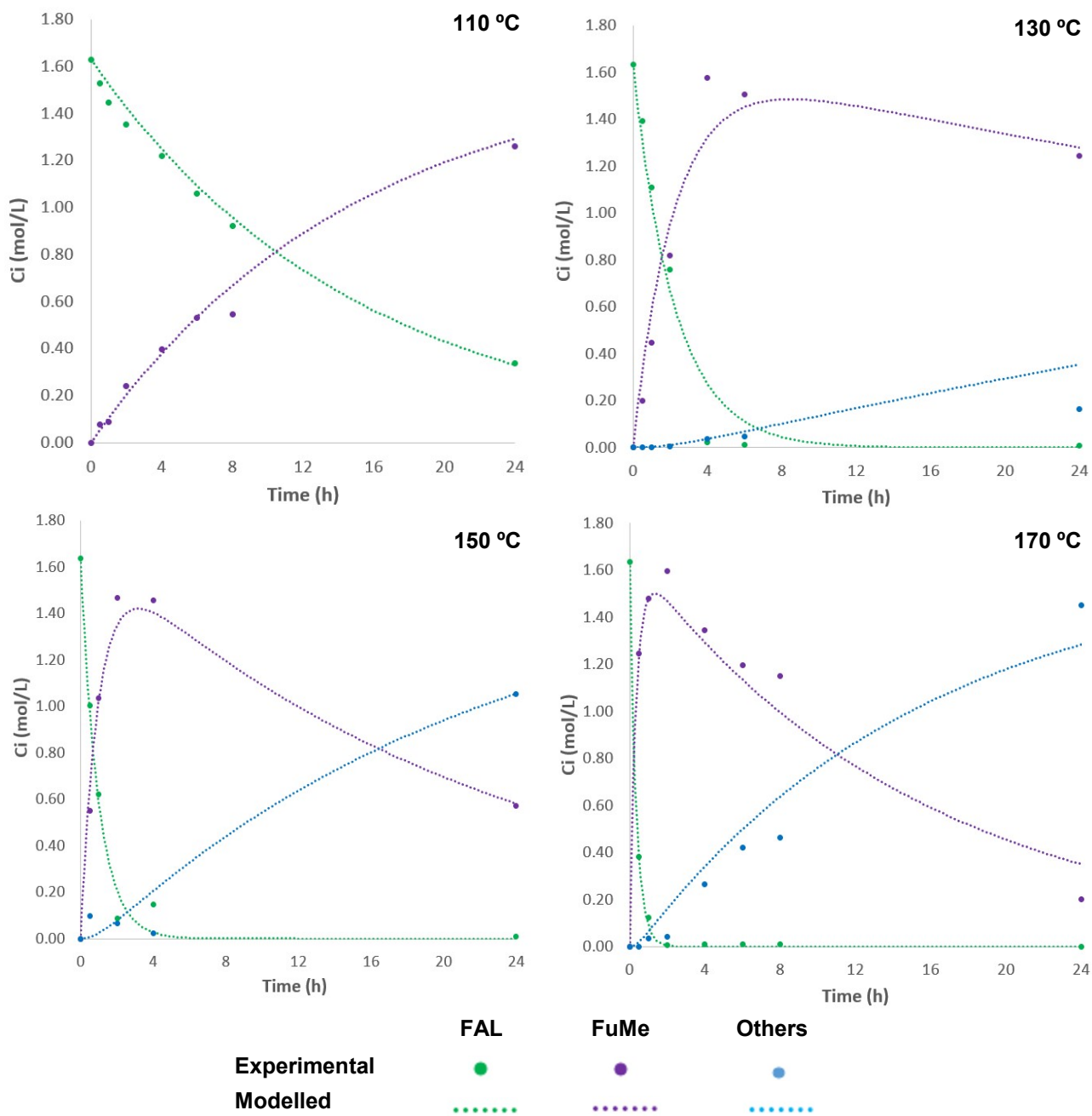


**Fig. ESI-5** Catalytic activity of UiO-66(Zr)-TFA2 and UiO-66(Zr)-TFA2-300 in the aldol condensation of FAL and MIBK. Reaction conditions: time = 4 h; temperature = 130 °C; MIBK/FAL molar ratio = 4; FAL/Cat mass ratio = 10.

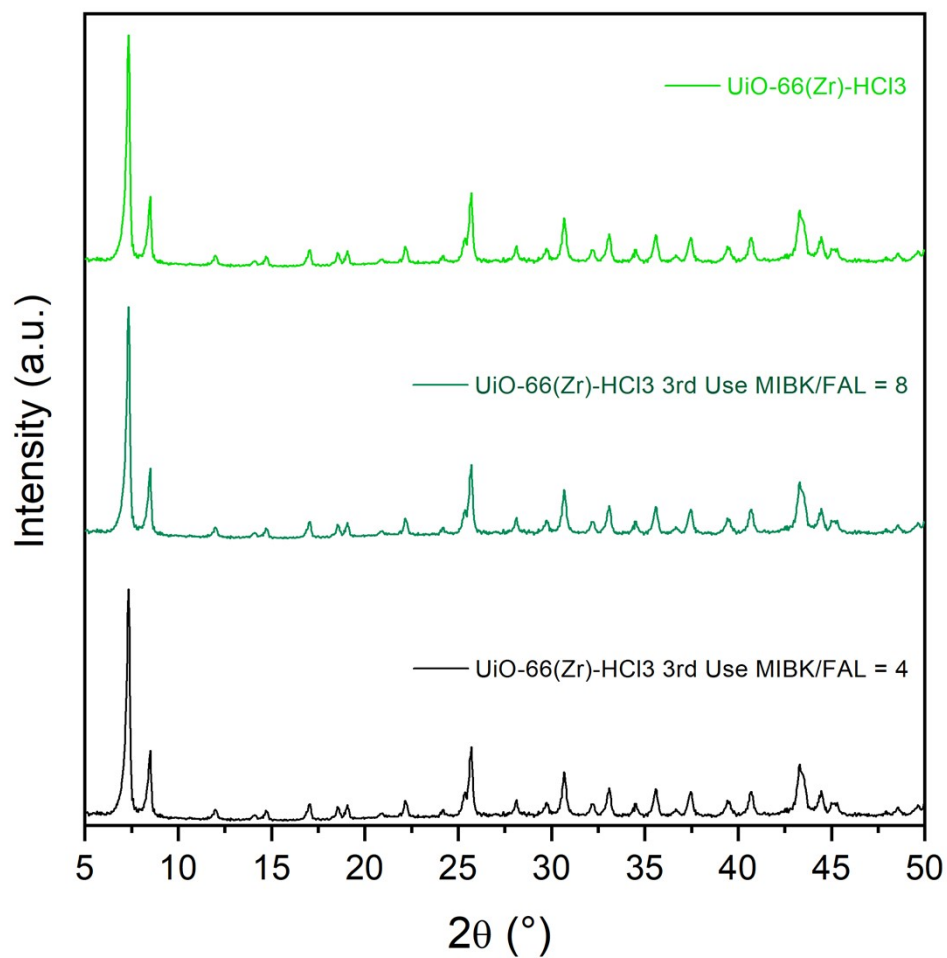




**Scheme ESI-1.** Transformations and constants considered for the kinetics analysis of the aldol condensation of FAL and MIBK.



**Fig. ESI-6.** Experimental (symbols) and modelled (dash lines) concentrations of the compounds involved in the aldol condensation of FAL and MIBK over UiO-66(Zr)-HCl<sub>3</sub>. Reaction conditions: MIBK/FAL molar ratio = 4/1; FAL/Cat mass ratio = 10/1.



**Fig. ESI-7.** Powder X-ray diffraction patterns of the UiO-66(Zr)-HCl<sub>3</sub>, fresh and after three consecutive uses in reaction under different dilution. Reaction conditions: time = 3 h; temperature = 130 °C; MIBK/FAL molar ratio = 4 (FAL/Cat = 10) and 8 (FAL/Cat = 5).